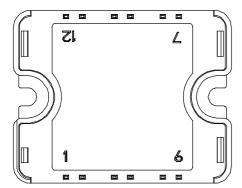


Full - Bridge CoolMOS & Trench + Field Stop® IGBT Power module

3 4 O1 OR1 O3 CR3 O4 7 O4 7 O4

Top switches : Trench + Field Stop IGBT® Bottom switches : CoolMOS<sup>TM</sup>



Pins 3/4 must be shorted together

Trench & Field Stop® IGBT Q1, Q3: V<sub>CES</sub> = 600V; I<sub>C</sub> = 50A @ Tc = 80°C

CoolMOS<sup>TM</sup> Q2, Q4:

 $V_{DSS} = 600V$ ;  $I_D = 36A$  @ Tc = 25°C

#### **Application**

• Solar converter

#### **Features**

#### • Q2, Q4 CoolMOSTM

- Ultra low R<sub>DSon</sub>
- Low Miller capacitance
- Ultra low gate charge
- Avalanche energy rated
- Very rugged
- Fast intrinsic diode

#### • Q1, Q3 Trench & Field Stop IGBT®

- Low voltage drop
- Switching frequency up to 20 kHz
- RBSOA & SCSOA rated
- Low tail current

#### • SiC Schottky Diode (CR1, CR3)

- Zero reverse recovery
- Zero forward recovery
- Temperature Independent switching behavior
- Positive temperature coefficient on VF
- Very low stray inductance
- Internal thermistor for temperature monitoring
- High level of integration

#### Benefits

- Outstanding performance at high frequency operation
- Direct mounting to heatsink (isolated package)
- Low junction to case thermal resistance
- Solderable terminals both for power and signal for easy PCB mounting
- Low profile
- RoHS Compliant

CAUTION: These Devices are sensitive to Electrostatic Discharge. Proper Handing Procedures Should Be Followed. See application note APT0502 on www.microsemi.com

All ratings @  $T_j = 25$ °C unless otherwise specified



### 1. Top switches

## 1.1 Top Trench + Field Stop IGBT® characteristics

## Absolute maximum ratings

Symbol	Parameter		Max ratings	Unit
$V_{CES}$	Collector - Emitter Breakdown Voltage		600	V
Ţ	Continuous Collector Current	$T_C = 25^{\circ}C$	80	
$I_{C}$	Continuous Conector Current	$T_C = 80$ °C	50	A
$I_{CM}$	Pulsed Collector Current	$T_C = 25^{\circ}C$	100	
$ m V_{GE}$	Gate – Emitter Voltage		±20	V
$P_{\mathrm{D}}$	Maximum Power Dissipation	$T_C = 25^{\circ}C$	176	W
RBSOA	Reverse Bias Safe Operating Area	$T_{\rm J} = 150^{\circ}{\rm C}$	100A @ 550V	

#### **Electrical Characteristics**

Symbol	Characteristic	Test Conditions	Min	Typ	Max	Unit	
$I_{CES}$	Zero Gate Voltage Collector Current	$V_{GE} = 0V$ , $V_{CE} =$			250	μA	
V <sub>CE(sat)</sub>	Collector Emitter Saturation Voltage	$V_{GE} = 15V$	$T_j = 25^{\circ}C$		1.5	1.9	V
V CE(sat)	Conector Emitter Saturation Voltage	$I_C = 50A$	$T_{j} = 150^{\circ}C$		1.7		v
$V_{GE(th)}$	Gate Threshold Voltage	$V_{GE} = V_{CE}, I_C = 600 \mu A$		5.0	5.8	6.5	V
$I_{GES}$	Gate – Emitter Leakage Current	$V_{GE} = 20V, V_{CE}$	=0V			600	nA

### **Dynamic Characteristics**

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit
Cies	Input Capacitance	$V_{GE} = 0V$			3150		
Coes	Output Capacitance	$V_{CE} = 25V$			200		pF
$C_{res}$	Reverse Transfer Capacitance	f = 1MHz			95		
$T_{d(on)}$	Turn-on Delay Time	Inductive Switch	ning (25°C)		110		
T <sub>r</sub>	Rise Time	$V_{GE} = \pm 15V$			45		
T <sub>d(off)</sub>	Turn-off Delay Time	$I_{C} = 50A$	$V_{\text{Bus}} = 300V$ $V_{\text{Bus}} = 50 \text{ A}$		200		ns
$T_{\rm f}$	Fall Time	$R_G = 8.2\Omega$		40			
$T_{d(on)}$	Turn-on Delay Time	Inductive Switch		120			
$T_{\rm r}$	Rise Time	$V_{GE} = \pm 15V$			50		ns
$T_{d(off)}$	Turn-off Delay Time	$V_{Bus} = 300V$ $I_{C} = 50A$			250		
$T_{\rm f}$	Fall Time	$R_G = 8.2\Omega$			60		
Eon	Turn-on Switching Energy	$V_{GE} = \pm 15V$	$T_j = 25^{\circ}C$		0.3		mJ
Eon	Turn-on Switching Energy	$V_{\text{Bus}} = 300 \text{V}$	$T_{\rm j} = 150^{\circ}{\rm C}$		0.43		1113
$E_{off}$	Turn-off Switching Energy	$I_{\rm C} = 50A$	$T_j = 25^{\circ}C$		1.35		mJ
Doff	Turn on Switching Ellergy	$R_G = 8.2\Omega$	$T_{j} = 150^{\circ}C$		1.75		1113
$R_{\text{thJC}}$	Junction to Case Thermal resistance					0.85	°C/W



### 1.2 Top SiC diode characteristics (CR1, CR3)

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit	
$V_{RRM}$	Maximum Peak Repetitive Reverse Voltage			600			V	
т	Maximum Reverse Leakage Current	V =600V	$T_j = 25^{\circ}C$		50	200	^	
$I_{RM}$	Waximum Reverse Leakage Current	$V_R=600V$ T	$T_i = 125$	$T_j = 125$ °C		100	1000	μΑ
$I_{F(AV)}$	Maximum Average Forward Current	50% duty cycle	Tc = 100°C		10		A	
$V_{\rm F}$	Diode Forward Voltage	$I_F = 10A$	$T_i = 25^{\circ}C$		1.6	1.8	V	
V F	Diode Forward Voltage		$T_i = 175$ °C		2	2.4	v	
Qc	Total Capacitive Charge	$I_F = 10A, V_R = 300V$ di/dt = 500A/ $\mu$ s			14		nC	
C	Total Capacitance	$f = 1MHz, V_R =$	200V		65		рF	
	Total Capacitance	$f = 1MHz, V_R =$	400V		50		pr.	
$R_{thJC}$	Junction to Case Thermal resistance					2.5	°C/W	

#### 2. Bottom switches

#### 2.1 Bottom CoolMOSTM characteristics

### Absolute maximum ratings

Symbol	Parameter		Max ratings	Unit
$V_{ m DSS}$	Drain - Source Breakdown Voltage		600	V
Ţ	Continuous Drain Current	$T_c = 25^{\circ}C$	36	
$I_{\mathrm{D}}$	Continuous Drain Current	$T_c = 80$ °C	27	A
$I_{DM}$	Pulsed Drain current		115	
$V_{GS}$	Gate - Source Voltage		±20	V
R <sub>DSon</sub>	Drain - Source ON Resistance		83	mΩ
$P_{D}$	Maximum Power Dissipation	$T_c = 25$ °C	250	W
$I_{AR}$	Avalanche current (repetitive and non repetitive)		20	A
$E_{AR}$	Repetitive Avalanche Energy		1	mJ
$E_{AS}$	Single Pulse Avalanche Energy		1800	1113

#### **Electrical Characteristics**

Symbol	Characteristic	Test Conditions	Min	Тур	Max	Unit
Ţ	Zero Gate Voltage Drain Current	$V_{GS} = 0V, V_{DS} = 600V$ $T_j = 25^{\circ}C$			100	
$I_{ m DSS}$	Zero Gate Voltage Drain Current	$V_{GS} = 0V, V_{DS} = 600V$ $T_j = 125^{\circ}C$			5000	μΑ
R <sub>DS(on)</sub>	Drain – Source on Resistance	$V_{GS} = 10V, I_D = 24.5A$			83	mΩ
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 3mA$	3	4	5	V
$I_{GSS}$	Gate – Source Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$			100	nA



### **Dynamic Characteristics**

Symbol	Characteristic	Test Conditions	Min	Typ	Max	Unit
$C_{iss}$	Input Capacitance	$V_{GS} = 0V ; V_{DS} = 25V$		7.2		nF
$C_{rss}$	Reverse Transfer Capacitance	f = 1MHz		0.041		111
$Q_{g}$	Total gate Charge	$V_{GS} = 10V$		250		
$Q_{gs}$	Gate – Source Charge	$V_{Bus} = 300V$		43		nC
$Q_{\mathrm{gd}}$	Gate – Drain Charge	$I_D = 36A$		135		
$T_{d(on)}$	Turn-on Delay Time	Inductive Switching (125°C)		21		
$T_{\rm r}$	Rise Time	$V_{GS} = 10V$		30		
$T_{d(off)}$	Turn-off Delay Time	$V_{Bus} = 400V$ $I_D = 36A$		240		ns
$T_{\mathrm{f}}$	Fall Time	$R_G = 5\Omega$		52		
$E_{on}$	Turn-on Switching Energy	Inductive switching @ 25°C $V_{GS} = 10V ; V_{Bus} = 400V$		531		μJ
E <sub>off</sub>	Turn-off Switching Energy	$I_D = 36A$ ; $R_G = 5\Omega$		590		μ
Eon	Turn-on Switching Energy	Inductive switching @ 125°C		762		1
$E_{\text{off}}$	Turn-off Switching Energy	$V_{GS} = 10V ; V_{Bus} = 400V$ $I_D = 36A ; R_G = 5\Omega$		725		μJ
$R_{thJC}$	Junction to Case Thermal resistance				0.5	°C/W

### **Source - Drain diode ratings and characteristics**

Symbol	Characteristic	Test Conditions		Min	Тур	Max	Unit
$I_S$	Continuous Source current		$Tc = 25^{\circ}C$		36		A
	(Body diode)		$Tc = 80^{\circ}C$		27		Λ
$V_{\mathrm{SD}}$	Diode Forward Voltage	$V_{GS} = 0V, I_S = -36A$				1.2	V
dv/dt	Peak Diode Recovery <b>1</b>					40	V/ns
+	Daniera Baranama Tima		$T_j = 25^{\circ}C$		210		200
t <sub>rr</sub>	Reverse Recovery Time	$I_S = -36A$ $V_R = 350V$	$T_j = 125$ °C		350		ns
	Reverse Recovery Charge	$V_R = 350V$ $di_S/dt = 100A/\mu s$	$T_j = 25$ °C		2		
$Q_{rr}$		αις, αι 10011/μ5	$T_{j} = 125^{\circ}C$		5.4		μC

• dv/dt numbers reflect the limitations of the circuit rather than the device itself.

 $I_S \leq \text{--} \ 36 A \qquad di/dt \leq 100 A/\mu s \qquad V_R \leq V_{DSS} \qquad T_j \leq 150 ^{\circ} C$ 



#### 3. Temperature sensor

 ${f NTC}$  (see application note APT0406 on www.microsemi.com for more information).

Symbol	Characteristic	Min	Тур	Max	Unit
R <sub>25</sub>	Resistance @ 25°C		50		kΩ
B <sub>25/85</sub>	$T_{25} = 298.15 \text{ K}$		3952		K

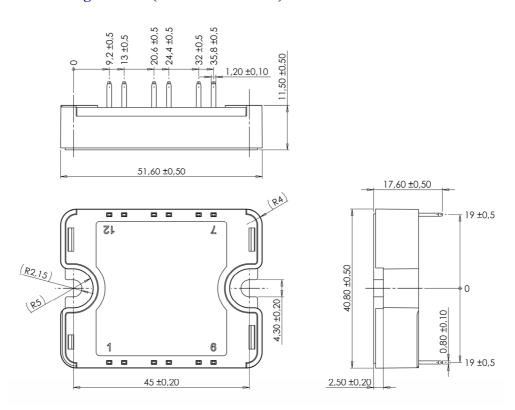
$$R_T = \frac{R_{25}}{\exp \left[ B_{25/85} \left( \frac{1}{T_{25}} - \frac{1}{T} \right) \right]} \quad \begin{array}{l} \text{T: Thermistor temperature} \\ R_T: \text{ Thermistor value at T} \end{array}$$

### 4. Package characteristics

Symbol	Characteristic			Min	Тур	Max	Unit
$V_{ISOL}$	RMS Isolation Voltage, any terminal to case $t = 1$	min, 50/60Hz		4000			V
$T_{J}$	Operating junction temperature range			-40		150*	
$T_{STG}$	Storage Temperature Range			-40		125	°C
$T_{\rm C}$	Operating Case Temperature					100	
Torque	Mounting torque	To heatsink	M4	2		3	N.m
Wt	Package Weight					80	g

Tj=175°C for Trench & Field Stop IGBT

### 5. SP1 Package outline (dimensions in mm)

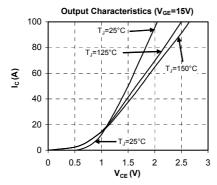


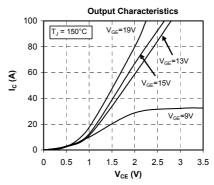
See application note 1904 - Mounting Instructions for SP1 Power Modules on www.microsemi.com

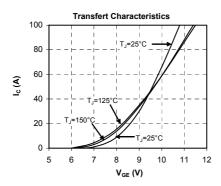


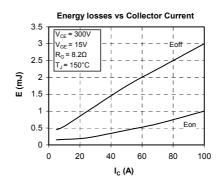
### 6. Top switches curves

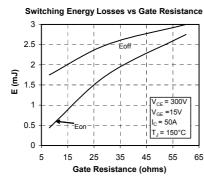
### 6.1 Top Trench + Field Stop IGBT® typical performance curves

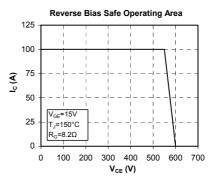


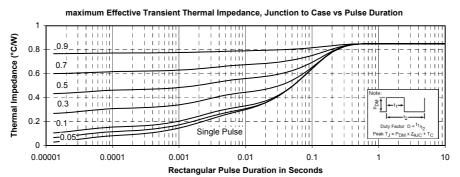






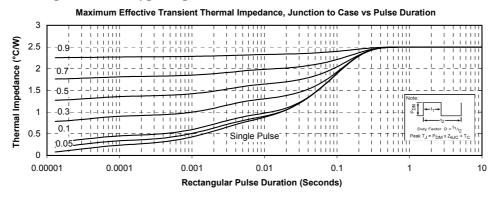


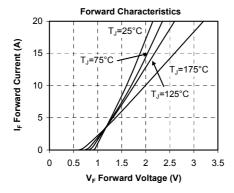


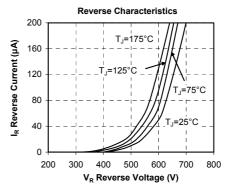


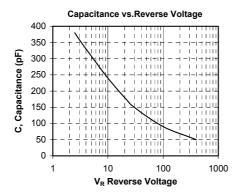


#### 6.2 Top SiC diode typical performance curves





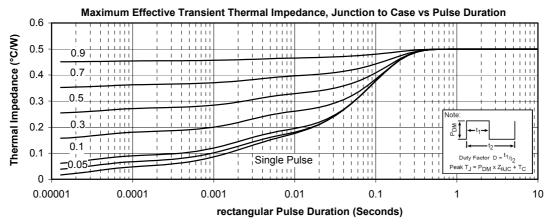


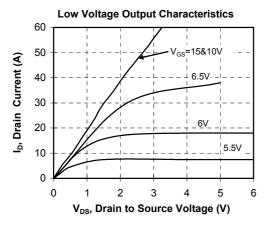


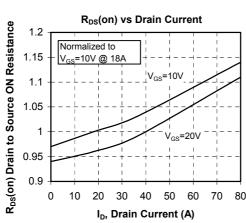


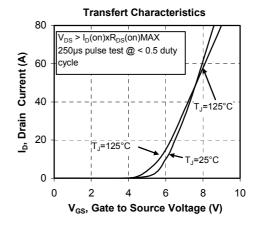
#### 7. Bottom switches curves

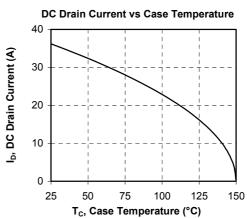
### 7.1 Bottom CoolMOS<sup>TM</sup> typical performance curves



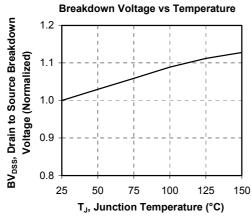


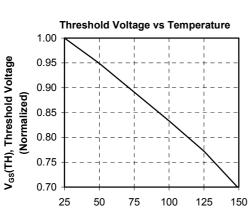




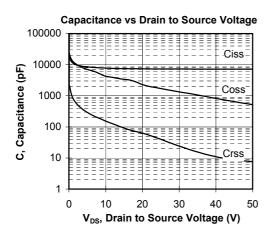


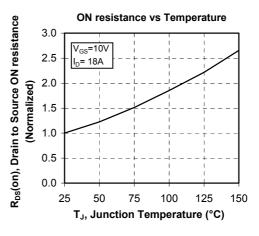


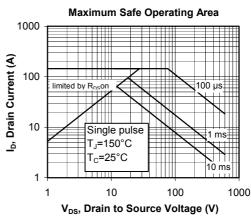


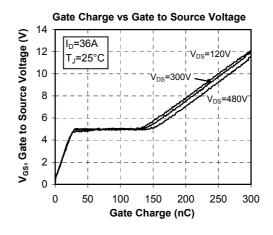


T<sub>C</sub>, Case Temperature (°C)

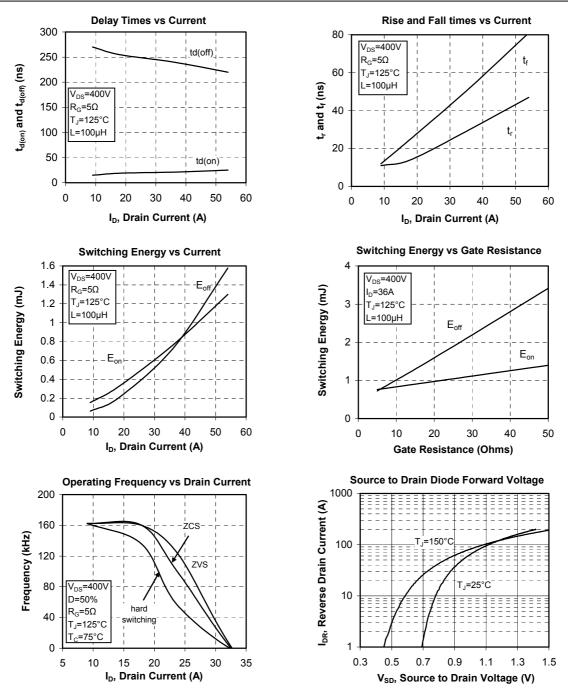












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